Electronic Supplementary Material (ESI) for Biomaterials Science.

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Supporting Information

Scanning ion-conductance microscopy technique for studying the topography and mechanical properties of Candida parapsilosis yeast microorganisms

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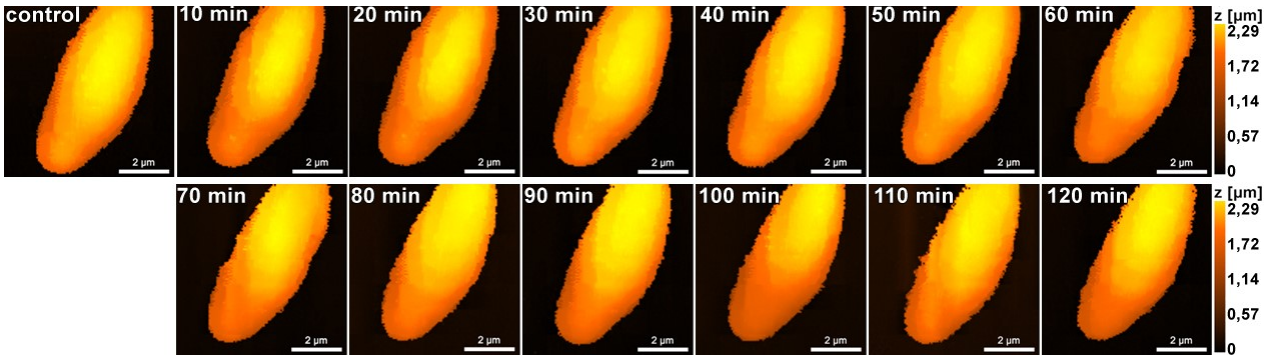

Figure S1 SICM images of a Candida parapsilosis control cell on repeated scans every 10 minutes for two hours.